

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 09/855,511 CHEN ET AL.	
		Examiner	Art Unit	Page 1 of 1 Lana N Le

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,396,879	05-2002	Yoshimura et al.	455/115.3
	B	US-2001/0023177	09-2001	Tanaka, Mitsuru	455/73
	C	US-6,532,357	03-2003	Ichikawa, Yasufumi	455/127.3
	D	US-6,386,788	04-2002	Fujioka et al.	330/51
	E	US-6,240,279	05-2001	Nitta et al.	455/127.2
	F	US-5,574,993	11-1996	Kobayashi et al.	455/127.1
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

